

Notice of References Cited	Application/Control No. 09/854,474	Applicant(s)/Patent Under Reexamination YAMANAKA, YOSHIMICHI	
	Examiner Christopher M. Keehan	Art Unit 1712	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	U	JP 2000-073010, machine translation obtained from http://www.ipdl.jpo.go.jp/homepg_e.ipdl .
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